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Sheet	1	of	2

	Complete If Known		
Application Number	09/787,189		
Filing Date	March 15, 2001		
First Named Inventor	Slater		
Group Art Unit			
Examiner Name			
Attorney Docket Number	5000.113		

U.S. PATENT DOCUMENTS						
Examiner Initials *	Cite No.1	U.S. Patent Docu Kind C Number (if know	ode ²	Name of Palentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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Examiner Initials*	Cite ' No.1	Foreign Patent Document Office ³ Number ⁴ Kind Code ⁵ (if known)		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ₆	
	9	wo	98/37584	A1	THE BOARD OF TRUSTEES OF THE UNIVERSITY OF ILLINOIS	08-27-1998		
٥V	10	JP	09082663		Fuji Electric Co. Ltd.	03-28-1997		
DV	11	EP	0276002	, A2	Hosiden Electronics Co., Ltd.	07-27-1988		
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Examiner Signature	Whiland	Date Considered	o1/22/04	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the

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Sheet 2 of 2

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		OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS	
Examiner Initials *	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
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